MOSFET – Power, Single N-Channel 40 V, 5.6 mΩ, 71 A

NVTYS005N04C

Features

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low RDS(on) to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Value	Unit
Drain-to-Source Voltage			40	V
Gate-to-Source Voltage			±20	V
	$T_{C} = 25^{\circ}C$	۱ _D	71	А
Steady	T _C = 100°C		50	
State	$T_{C} = 25^{\circ}C$	PD	50	W
	$T_{C} = 100^{\circ}C$		25	
	T _A = 25°C	۱ _D	18	А
Steady	Steady T _A = 100°C		13	
State	$T_A = 25^{\circ}C$	PD	3.1	W
	T _A = 100°C		1.6	1
T _A = 25	$T_A = 25^{\circ}C$, $t_p = 10 \ \mu s$		308	А
Operating Junction and Storage Temperature Range		T _J , T _{stg}	–55 to +175	°C
Source Current (Body Diode)			42	А
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 4.6 A)		E _{AS}	146	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		ΤL	260	°C
	ge ge Steady State Steady State T _A = 25 Storage T Diode) Source Av Soldering F	ge ge T _C = 25°C T _C = 100°C T _C = 25°C T _C = 100°C T _C = 100°C T _C = 100°C T _A = 25°C T _A = 25°C T _A = 100°C T _A = 25°C T _A = 100°C	$\begin{array}{c c c c c c } \hline & & & & & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline ge & & & & & & & \\ \hline \hline ge & & & & & & & \\ \hline \hline ge & & & & & & & \\ \hline \hline Steady & & & & & & \\ \hline T_C & = 100^\circ C & & & & \\ \hline \hline T_C & = 100^\circ C & & & \\ \hline \hline T_A & = 100^\circ C & & & \\ \hline \hline T_A & = 25^\circ C & & P_D \\ \hline \hline T_A & = 100^\circ C & & \\ \hline \hline T_A & = 100^\circ C & & \\ \hline \hline T_A & = 100^\circ C & & \\ \hline \hline T_A & = 25^\circ C , t_p & = 10 \ \mu s & & & & \\ \hline I & Storage Temperature & & & \\ \hline \hline Diode) & & & & \\ \hline Source Avalanche & & & \\ \hline \hline \hline \\ \hline \hline \end{array} $	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	3.0	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	47.7	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Psi (Ψ) is used as required per JESD51–12 for packages in which substantially less than 100% of the heat flows to single case surface.

3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.

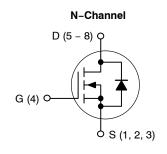
4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
40 V	5.6 mΩ @ 10 V	71 A	





3.3x3.3 CASE 760AD

MARKING DIAGRAM



005N04C = Specific Device Code

A = Assembly Location

WL = Wafer Lot

Y = Year

W = Work Week

(Note: Microdot may be in either location)

ORDERING INFORMATION

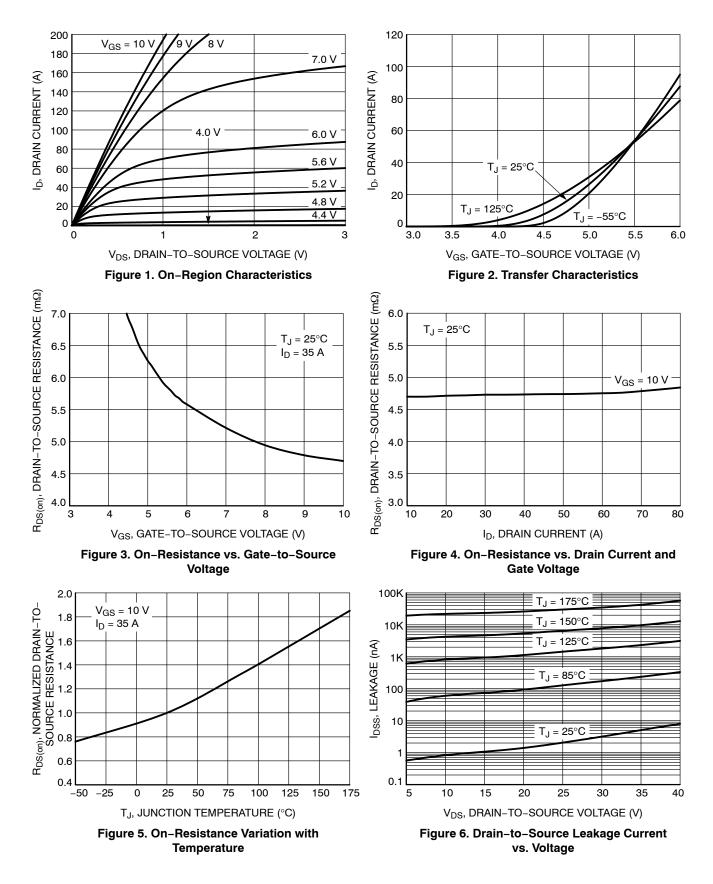
See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted)

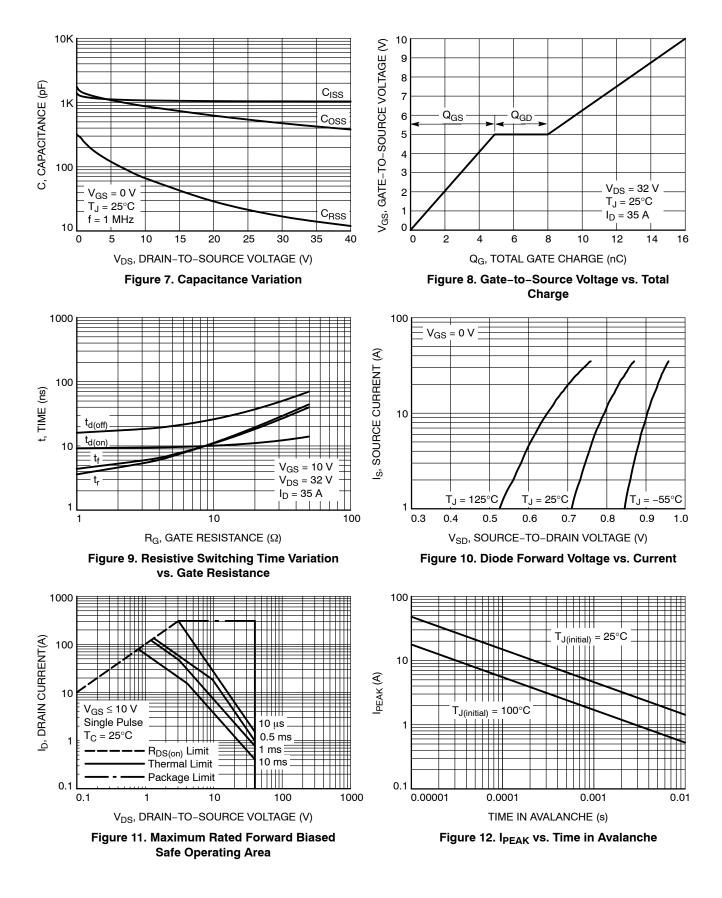
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	-	-			-		-
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I _D = 250 μ A		40			V
Zero Gate Voltage Drain Current	I _{DSS}	DSS $V_{GS} = 0 V,$ $V_{DS} = 40 V$ $T_J = 25^{\circ}C$ $T_J = 125^{\circ}C$	$T_J = 25^{\circ}C$			10	μA
			T _J = 125°C			250	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = 20 V				100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$) = 40 μA	2.5		3.5	V
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I	_D = 35 A		4.6	5.6	mΩ
Forward Transconductance	9 _{FS}	V _{DS} = 5 V, I _C	₀ = 35 A		59		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{iss}				1000		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = V _{DS} = 2	1.0 MHz, 5 V		530		
Reverse Transfer Capacitance	C _{rss}	• US - 25 v			22		1
Threshold Gate Charge	Q _{G(TH)}	V_{GS} = 10 V, V_{DS} = 32 V, I_{D} = 35 A			2.9		nC
Gate-to-Source Charge	Q _{GS}				4.9		
Gate-to-Drain Charge	Q _{GD}				3.7		1
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 10 V, V_{DS} = 32 V, I_{D} = 35 A			16		nC
SWITCHING CHARACTERISTICS (No	te 6)						
Turn-On Delay Time	t _{d(on)}				9.2		ns
Rise Time	t _r	V _{GS} = 10 V, V _E	_{0S} = 32 V,		3.6		
Turn-Off Delay Time	t _{d(off)}	$I_{\rm D} = 35 {\rm A}, {\rm R}_{\rm O}$	_G = 1 Ω		16		
Fall Time	t _f	1			4.4		
DRAIN-SOURCE DIODE CHARACTER	RISTICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$		0.86	1.2	V
		$I_{\rm S} = 35 \text{A}$ $T_{\rm J} = 125^{\circ}\text{C}$	T _J = 125°C		0.75		1
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _S /dt = 100 A/µs, I _S = 35 A			35		ns
Charge Time	t _a				17		1
Discharge Time	t _b				18		1
Reverse Recovery Charge	Q _{RR}	1			16		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
5. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

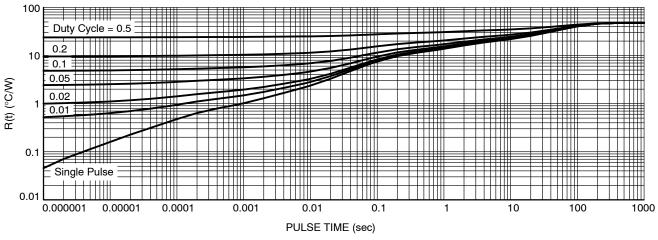


Figure 13. Thermal Characteristics

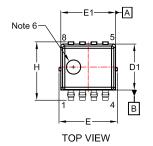
DEVICE ORDERING INFORMATION

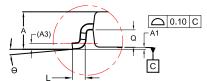
Device	Marking	Package	Shipping [†]
NVTYS005N04CTWG	005N 04C	LFPAK33 (Pb–Free)	3000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

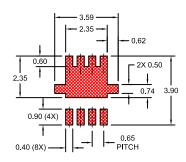
PACKAGE DIMENSIONS

LFPAK8 3.3x3.3, 0.65P CASE 760AD ISSUE E



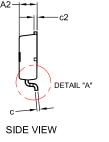


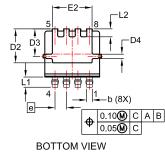
DETAIL 'A' SCALE: 2:1



LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.





NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS OR BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- 6. OPTIONAL MOLD FEATURE.

DIM	MILLIMETERS			
DIW	MIN.	NOM.	MAX.	
А	0.95	1.05	1.15	
A1	0.00	0.05	0.10	
A2	0.95	1.00	1.05	
A3		0.15 REI	F	
b	0.27	0.32	0.37	
С	0.12	0.17	0.22	
c2	0.12	0.17	0.22	
D1	2.50	2.60	2.70	
D2	1.82	1.92	2.02	
D3	1.46	1.56	1.66	
D4	0.20	0.25	0.30	
E	3.20	3.30	3.40	
E1	3.00	3.10	3.20	
E2	2.15	2.25	2.35	
е	().65 BSC	;	
Н	3.20	3.30	3.40	
L	0.25	0.37	0.50	
L1	0.48	0.58	0.68	
L2	0.35	0.45	0.55	
Q	0.45	0.50	0.55	
θ	0°	4°	8°	

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